PTO/SB/08A (10-01)

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Substitute for form 1449A/PTO Complete if Known Application No. 10/660,984 INFORMATION DISCLOSURE Filing Date September 12, 2003 STATEMENT BY APPLICANT **First Named Inventor** Steven W. Meeks Art Unit 2877 Examiner Name Tu Nguyen Sheet of Attorney Docket Number 20830-08288

			U.S. PAT	ENT DOCUMENTS
		Document No.		
Examiner Initials*	Cite No.1	Number - Kind Code <sup>2</sup> (if known)	Date MM-YYYY	Name of Patentee or Applicant of Cited Document
P	A1	US-6,639,662	10-2003	Vaez-Iravani et al.
Ta	A2	US-6,034,378	03-2000	Shiraishi
The	A3	US-5,715,058	02-1998	Bohnert et al.
TW	A4	US-5,586,101	12-1996	Gage et al.
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	FOREIGN PATENT DOCUMENTS				
		Foreign Patent Document			
Examiner Initials*	Cite No. <sup>1</sup>	Country Code <sup>3</sup> – Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	To

		OTHER REFERENCES - NON-PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T⁰

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7	Substitute for	form 1449	APTO		Compl t if Known	
INFO	DMATIO	N DIS	CLOSURE	Application No.	10/660,984	
			PPLICANT	Filing Date	September 12, 2003	
SIAI	CIAICIAI	DIA	PPLICANT	First Named Inv ntor	Steven W. Meeks	
				Art Unit	2877	
				Examiner Name	T. Nguyen	
Sheet	1	of	4	Attorney Docket Number	20830-08288	

_			U.S. PATE	NT DOCUMENTS
		Document No.		
Examiner Initials*	Cite No.1	Number – Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
TV	A1	3,885,875	05/27/1975	Rosenfeld et al.
1	A2	4,332,477	06/01/1982	Sato
	A3	4,585,348	04/29/1986	Chastang et al.
	A4	4,668,860	05/26/1987	Anthon
	A5	4,870,631	09/26/1989	Stoddard
	A6	4,873,430	10/10/1989	Juliana et al.
	A7	5,017,012	05/21/1991	Merritt, Jr. et al.
	A8	5,129,724	07/14/1992	Brophy et al.
	A9	5,189,481	02/23/1993	Jann et al.
	A10	5,196,906	03/23/1993	Stover et al.
	A11	5,270,794	12/14/1993	Tsuji et al.
	A12	5,293,216	03/08/1994	Moslehi
	A13	5,313,542	05/17/1994	Castonguay
	A14	5,406,082	04/11/1995	Pearson et al.
	A15	5,416,594	05/16/1995	Gross et al.
	A16	5,446,549	08/29/1995	Mazumder et al.
	A17	5,463,897	11/07/1995	Prater et al.
	A18	5,608,527	03/04/1997	Valliant et al.
	A19	5,610,897	03/11/1997	Yamamoto et al.
	A20	5,633,747	05/27/1997	Nikoonahad
	A21	5,644,562	07/01/1997	de Groot
	A22	5,694,214	12/02/1997	Watanabe et al.
	A23	5,726,455	03/10/1998	Vurens
	A24	5,748,305	05/05/1998	Shimono et al.
	A25	5,777,740	07/07/1998	Lacey et al.
	A26	5,798,829	08/25/1998	Vaez-Iravani
	A27	5,864,394	01/26/1999	Jordan, III et al.
	A28	5,875,029	02/23/1999	Jann et al.
	A29	5,880,838	03/09/1999	Marx et al.
72	A30	5,903,342	05/11/1999	Yatsugake et al.

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			U.S. PATE	NT DOCUMENTS
		Document No.		
Examiner Initials*	Cite No.1	Number - Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
N	A31	5,951,891	09/14/1999	Barenboim et al.
	A32	5,978,091	11/02/1999	Jann et al.
	A33	5,985,680	11/16/1999	Singhal et al.
	A34	5,986,761	11/16/1999	Crawforth et al.
	A35	5,986,763	11/16/1999	Inoue
	A36	5,995,226	11/30/1999	Abe et al.
	A37	6,081,325	06/27/2000	Leslie et al.
	A38	6,088,092	07/11/2000	Chen et al.
	A39	6,091,493	07/18/2000	Stover et al.
	A40	6,107,637	08/22/2000	Watanabe et al.
	A41	6,118,525	09/12/2000	Fossey et al.
	A42	6,134,011	10/17/2000	Klein et al.
	A43	6,157,444	12/05/2000	Tomita et al.
	A44	6,169,601	01/2001	Eremin et al.
	A45	6,172,752	01/09/2001	Haruna et al.
	A46	6,201,601B1	03/13/2001	Vaez-Iravani et al.
	A47	6,248,988	06/19/2001	Krantz
	A48	6,271,916B1	08/07/2001	Marxer et al.
	A49	6,307,627	10/23/2001	Vurens
	A50	6,353,222B1	03/05/2002	Dotan
	A51	.6,384,910B2	05/07/2002	Vaez-Iravani et al.
	A52	6,509,966B2	01/21/2003	Ishiguro et al.
	A53	6,542,248B1	04/01/2003	Schwarz
TH	A54	6,603,542	08/2003	Chase et al.

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			U.S. PATE	ENT DOCUMENTS	
		Document No.			
Examiner Initials*	Cite No.1	Number – Kind Code <sup>2</sup> (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	
	•		FOREIGN PA	TENT DOCUMENTS	
		Foreign Patent Document			
Examiner Initials*	Cite No. <sup>1</sup>	Country Code <sup>3</sup> – Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	T <sub>e</sub>
TN	B1	WO 98/52019	11/19/1998	Technische Universiteit Delft	
PW	B2	JP 3-221804	09/30/1991	NEC Corp	

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		OTHER REFERENCES - NON-PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>6</sup>
P	C1	W.C. Leung, W. Crooks, H. Rosen and T. Strand, An Optical Method Using a Laser and an Integrating Sphere Combination for Characterizing the Thickness Profile of Magnetic Media, Sept. 1989, IEEE Transaction on Magnetics, Vol. 25, No. 5. Pages 3659-3661.	
	C2	Steven W. Meeks, Walter E. Weresin, and Hal J. Rosen, <i>Optical Surface Analysis of the Head-Disk-Interface of Thin Film Disks</i> , January 1995, Transactions of the ASME, Journal of Tribology, Vol. 117, pages 112-118.	
	C3	Steven Meeks, Maxtor and Rusmin Kudinar, <i>The Next Battleground: Head-Disk Interface</i> , March 1998, Data Storage, Test & Measurement, pages 29-30, 34 and 38.	
	C4	Laser Scanning Surface Profilometer, [online], August 1970, [retrieved January 29, 2001], Pages 789-790, Retrieved from the Internet: <url: http:="" tdb?&order="7OC101758.&lt;/td" tdbs="" www.delphion.com=""><td></td></url:>	
The	C5	Meeks, Steven W.: "A Combined Ellipsometer, Reflectometer, Scatterometer and Kerr Effect Microscope for Thin Film Disk Characterization," Machine Vision Applications in Industrial Inspection VIII, Proceedings of SPIE, vol. 3966, 2000, pages 385-391, XP001085220.	

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